

XRF Coating Thickness Gauge

SFT-110

Simply set the sample then measure

Thin 50nm gold plating measurement
in 10 seconds

Standard samples not required

Easy point designation from wide area view
of entire samples



The SFT-110, the latest model in our line of SFT series coating thickness gauges first introduced in 1978, features the latest developments in operability and software and dramatically improves throughput of coating thickness measurements.

SFT-110

【Primary Functions】

Set sample and start measuring

A new auto focus function allows for focus of the observation optics system within seconds. The level of ease for positioning is greatly enhanced.

Measure 50nm gold plating in 10 seconds

Optimized layout maximizes sensitivity for collimator (0.1, 0.2mm) improving accuracy of thin film measurement.

Standard-less measurement now available

Thin film FP software (max 5 layers) has been modified to allow thickness standard-less measurement. Multi-layer and alloy plating measurement capable.

Wide view of entire samples makes spot selection easy

Wide area observation system allows for entire sample image (max 250 x 200mm) to be observed at once. In addition, a desired measurement area can be designated with ease.

【Product Specification】

Measurable Elements	Atomic Number 22 (Ti) ~ 83 (Bi)
X-ray Source	Small Air-cooled X-ray Tube Tube Voltage: 50kV Tube Current: 1mA
Detector	Proportional Counter Detector
Collimator	Round: 0.1mm and 0.2mm Φ
Sample Observation	CCD Camera
Focus Adjustment	Laser Pointer (Automatic)
Filter	Primary Filter (Automatic Switching)
Sample Stage (Table Size) (Stage Travel)	260(W)×210(D)mm 250(X)×200(Y)×150(Z)mm
Operation (Xray Station)	PC with 19inch LCD
Application Software	Film Analysis(FP) (Maximum 5 Layers, 10 Elements) Calibration Curve Method
Data Processing	Microsoft® Excel Microsoft® Word
Safety Function	Interlocked Chamber Door Sample Collision Prevention
Other Functions	Self-Diagnosis

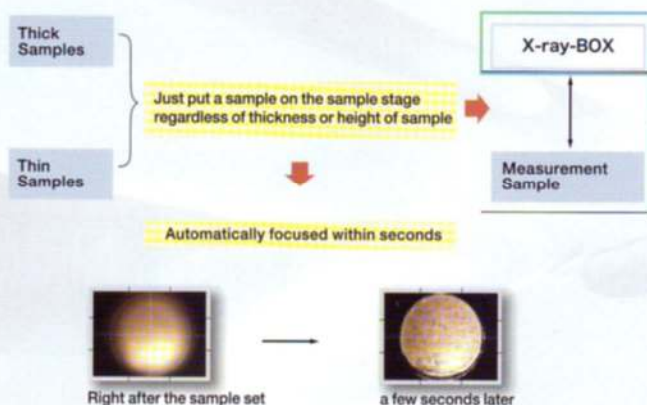
【Options】

- Image Processing Software
- Bulk FP Software (Material Composition Analysis)
- Bulk Calibration Curve Software (Plating Solution Analysis)
- Manual Stage
- Fixed Sample Stage
- Collimator: 4 types set (0.05, 0.1, 0.2, & 0.025 x 0.4mm)

New Functions

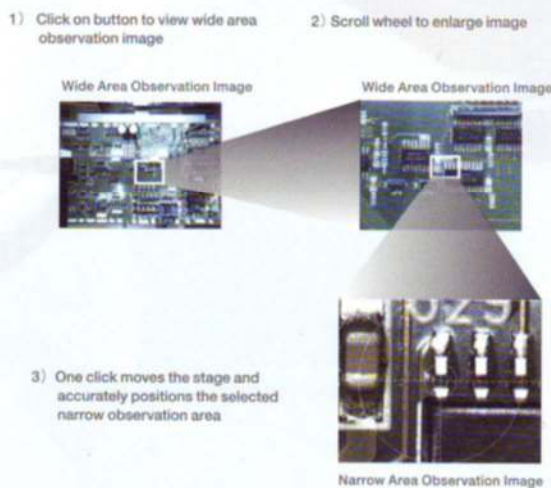
Auto Focus Function

Automatic Focus within seconds for both tall and low samples



Wide Area Observation Function

Narrow images can be selected from a wide area observation image of a sample



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